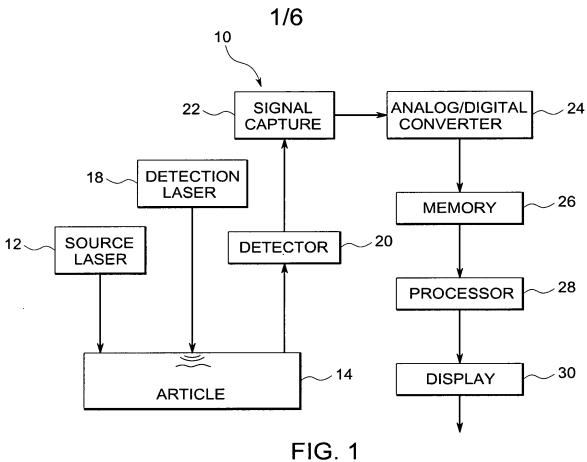
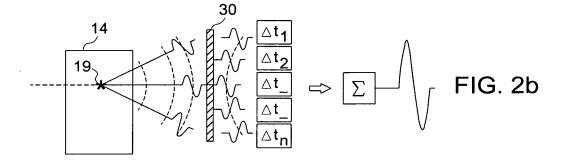


Inventor: Peter William Lorraine et al.
Title: Method for Detection of Defects in

Anisotropic Materials



 $\begin{array}{c}
 & 30 \\
 & 17 \\
 & 17 \\
 & 17
\end{array} \Rightarrow \begin{array}{c}
 & \Sigma \\
 & 17
\end{array}$ FIG. 2a





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Anisotropic Materials

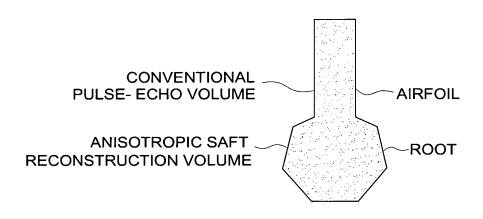


FIG.3

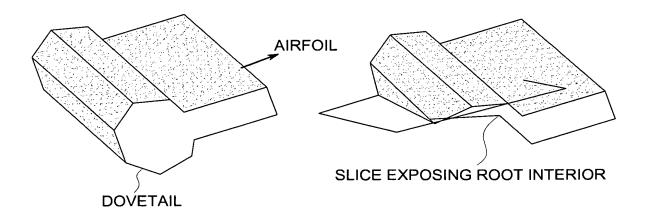


FIG.4



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Anisotropic Materials

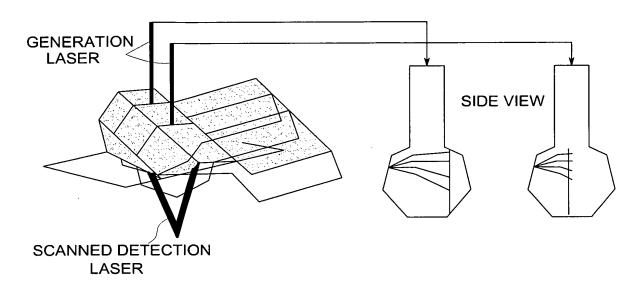


FIG.5

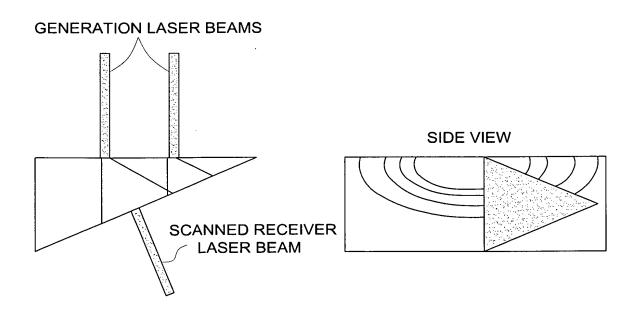


FIG.6



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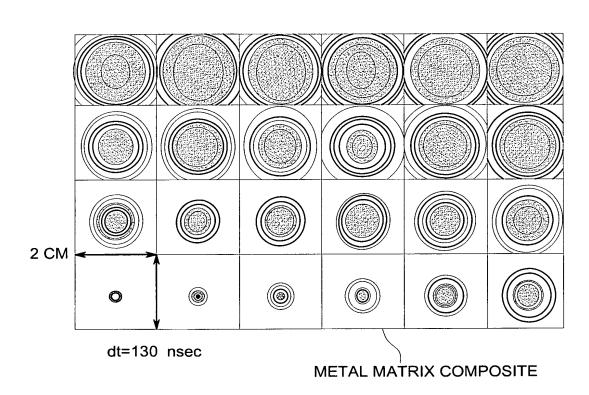


FIG. 7



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Anisotropic Materials

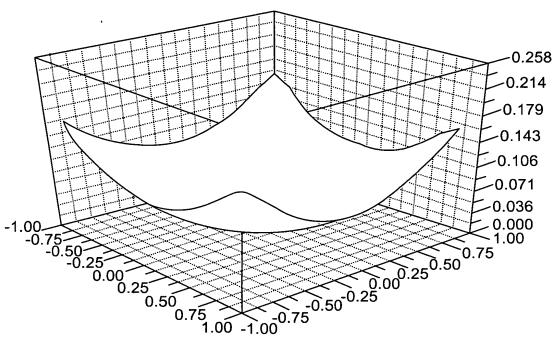


FIG. 8

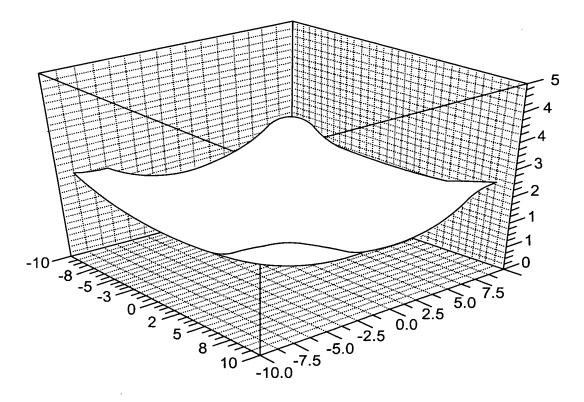


FIG. 9



Inventor: Peter William Lorraine et al. Title: Method for Detection of Defects in

Anisotropic Materials

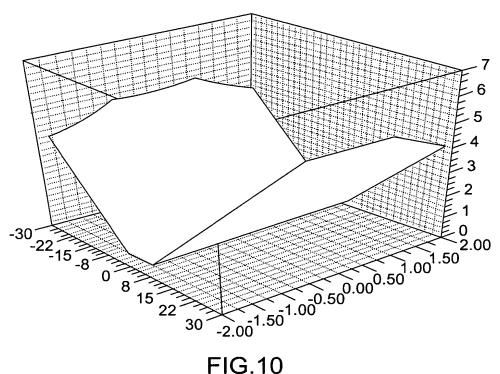


FIG.10

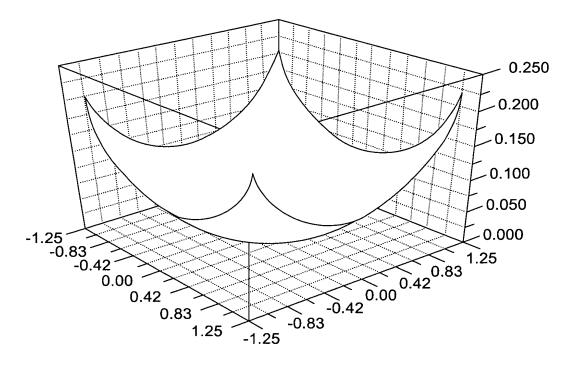


FIG.11